

<b>Search Notes</b>  <b>*1054286</b> <b>3*</b>	<b>Application/Control No.</b> 10542863	<b>Applicant(s)/Patent Under Reexamination</b> KANEKO, MASAMICHI
	<b>Examiner</b> CHRISTOPHER DEMEREE	<b>Art Unit</b> 3782

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
229	125.14, 125.15, 125.42	9/3/2009	CD
220	278	3/4/2010	CD
229	204	6/28/2010	CD

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Conducted a PLUS search on the application	9/3/2009	CD
Conducted a text search for (plug and tamper) within (229/125.17 or 229/125.09 or B65D 43/00 or B65D 5/74)	9/3/2009	CD
Consulted primary examiner, Robin Hylton, for search help. 220/277, 278 and 222/80, 81 were suggested	3/4/2010	CD
Conducted a text search for (pour\$4 WITH spout) and (220/277 or 222/80 or 222/81)	3/4/2010	CD
Updated search	6/28/2010	CD
Consulted primary examiner, Gary Elkins, for search help. 229/204 was suggested	6/28/2010	CD
Conducted a text search for ((pour\$3 WITH spout) and cutt\$3) and (222/83 or 222/83.5 or 222/85 or 222/86 or 222/88)	12/19/2010	CD

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
229	125.14, 125.15, 125.42, 204, 125.17, 125.09	12/19/2010	CD
220	278, 277	12/19/2010	CD
222	80, 81, 83, 85, 86, 87, 88	12/19/2010	CD

/CHRISTOPHER DEMEREE/  
Examiner.Art Unit 3782